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SHEET 1 OF 1

Form PTO 1449 (Modified)	1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. 255261US0PCT		SERALINO 501557 New Det Application	
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	AY						
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*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in							